

Notice of References Cited		Application/Control No. 10/574,367	Applicant(s)/Patent Under Reexamination JUTTE ET AL.	
		Examiner VAN T. PHAM	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,815,059 A	03-1989	Nakayama et al.	369/44.24
*	B US-5,260,828 A	11-1993	Londono et al.	359/565
*	C US-5,627,847 A	05-1997	Leger, James R.	372/9
*	D US-5,978,148 A	11-1999	Oono et al.	359/668
*	E US-6,072,579 A	06-2000	Funato, Hiroyoshi	356/457
*	F US-6,084,844 A	07-2000	Takeda, Tadashi	369/112.1
*	G US-6,154,326 A	11-2000	Ueyanagi et al.	359/819
*	H US-6,191,889 B1	02-2001	Maruyama, Koichi	359/566
*	I US-6,327,241 B1	12-2001	Boutaghou et al.	369/300
*	J US-7,301,881	11-2007	Itonaga, Makoto	369/112.23
*	K US-2003/0026190 A1	02-2003	Hendriks et al.	369/112.28
*	L US-6,590,708 B2	07-2003	Nakai et al.	359/558
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.